

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/004,019	<b>Applicant(s)/Patent under Reexamination</b> TOH ET AL.
	<b>Examiner</b> Shin-Hon Chen	<b>Art Unit</b> 2131

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
713	168,178	11/29/2005	S.C.
709	205	2/23/2005	S.C.
380	30	2/23/2005	S.C.